XOPT

Monday, 19 April

[XOPT-1-01] 9:30-9:40 Opening Remarks

Chair: Tetsuya Ishikawa RIKEN SPring-8 Center

[XOPT-2] 9:40-10:40 Advances in X-ray mirror

Chair: Takashi Kimura The University of Tokyo

X0PT-2-01 9:40

Advanced X-ray optics and metrology development at NSLS-II

Invited

Invited

Mourad Idir, Lei Huang, Tianyi Wang BNL/NSLS-II

During this talk, we will present our recent work on our newly established stitching interferometry platform, and our upgraded Nano Surface Profiler (NSP) for synchrotron mirror metrology. Thanks to these new metrology capabilities, we have developed our in house Ion Beam Figuring deterministic polishing system. Some new achieved results will be shown during the talk.

XOPT-2-02 10:10

Development of sub-micron soft x-ray free-electron laser focusing system at SACLA

Hiroto Motoyama The University of Tokyo

Ellipsoidal mirrors are promising optics for focusing soft x-rays down to sub-micromtre size without chromatic aberration. A soft x-ray focusing system combining an ellipsoidal mirror and a K-B mirror was developed at SACLA. The focused beam size is 500 x 550 nm with a maximum peak intensity of ~10¹⁶ W/cm² at the photon energy of 100 eV. The microscopic properties of materials having absorption edges in the soft x-ray region will be investigated with the system.

[XOPT-3] 11:00-12:00 X-ray optics Chair: Taito Osaka

RIKEN SPring-8 Center

XOPT-3-01 11:00

Wave-optical simulation for soft X-ray focusing optics using coherent mode decomposition

Yoko Takeo^{1,2}, Takashi Tanaka³, Yasunori Senba^{2,3}, Haruhiko Ohashi^{2,3}, Hidekazu Mimura¹

The University of Tokyo, ²Japan Synchrotron Radiation Research Institute (JASRI), ³RIKEN SPring-8 Center (RSC)

Spatial and temporal coherence of the soft X-ray focusing beam was estimated using wave-optical calculation with coherent mode decomposition. Quality of reconstructed images in ptychography measurement was compared between simulation and experimental results.

XOPT-3-02 11:15

Processing a micro-channel-cut crystal monochromator using Ni wire for reflection self-seeded X-ray free-electron laser

Shotaro Matsumura¹, Shota Nakano¹, Yasuhisa Sano¹, Taito Osaka^{1,2}, Ichiro Inoue², Makina Yabash², Kazuto Yamuchi¹ ¹*Osaka University, PalkEN SPring-8 Center* A high-quality channel-cut crystal monochromator with a gap width of ~100 µm is indispensable for reflection selforaded X was fraze locative a locar. Wa second

seeded X-ray free-electron laser. We report the details about instrument and results of processing the crystal.

XOPT-3-03 11:30

Optimization of mirror deformation method for hybrid bender combining mechanical and piezoelectric bending Yuka Nishioka¹. Takato Inoue¹.

Satoshi Matsuyama², Junki Sonoyama³, Kazuteru Akiyama³, Hiroki Nakamori⁴, Yasuhisa Sano¹, Yoshiki Kohmura⁵, Makina Yabashi⁵, Tetsuya Ishikawa⁵, Kazuto Yamauchi¹ *10saka University, ²Nagoya University, ³TOYAMA, ⁴JTEC Corporation, ⁵RIKEN/Spring-8* We will discuss the optimal deformation

method for the hybrid bender combining mechanical and piezoelectric bending and the achievable accuracy of this method.

XOPT-3-04 11:45

Development of sub-5 nm focusing system based on precise deformable mirrors

Takato Inoue¹, Satoshi Matsuyama^{1,2}, Yuto Tanaka¹, Kohei Futamura¹, Yoshio Ichii³, Jumpei Yamada⁴, Yasuhisa Sano¹, Yoshiki Kohmura⁴, Makina Yabashi^{4,5}, Tetsuya Ishikawa⁴, Kazuto Yamauchi¹ ¹Osaka University, ²Nagoya University, ³JTEC Corporation, ⁴RIKEN SPring-8 Center, ⁵Japan Synchrotron Radiation Research Institute To focus X-ray down to sub-5 nm, shape error on mirrors should be less than 0.6 nm PV. We installed a deformable mirror. In FEM simulation, the mirror could correct a shape error produced by fabrication processes.

[XOPT-4] 13:00-14:00 Wavefront / Imaging

Chair: Hiroto Motoyama The University of Tokyo

XOPT-4-01 13:00

Single-grating interferometer for hard X-ray sub-10nm focusing mirror system

Jumpei Yamada¹, Satoshi Matsuyama², Nami Nakamura³, Takato Inoue³, Taito Osaka¹, Ichiro Inoue¹, Hirokatsu Yumoto⁴, Takashi Koyama⁴, Haruhiko Ohashi⁴, Kazuto Yamauchi³, Makina Yabashi¹ ¹*RIKEN SPring-8 Center*, ²*Nagoya University*, ³*Osaka University*, ⁴*JASRI* X-ray single-grating interferometry was applied to conduct accurate wavefront corrections for hard X-ray nanofocusing mirrors. Systematic errors in the interferometer were carefully examined, and the mirror shapes were directly corrected usino a differential deposition technique

XOPT-4-02 13:15

Development of wavefront sensing in full-field X-ray microscopy Yuto Tanaka¹ Satoshi Matsuyama^{1,2}

based on the measured wavefront errors.

Yuto Tanaka¹, Satoshi Matsuyama^{1,2}, Takato Inoue¹, Nami Nakamura¹, Jumpei Yamada^{1,3}, Yoshiki Kohmura³, Makina Yabashi³, Kazuhiko Omote⁴, Tetsuya Ishikawa³, Kazuto Yamauchi¹ *¹Osaka University, ²Nagoya University, ³RIKEN SPring-8 Center, ⁴Rigaku Corporation* We proposed an in-situ wavefront measurement based on the intensity information near the focus. Applying this method, we were able to measure wavefront aberrations of the AKB mirrors in the magnifying geometry.

XOPT-4-03 13:30

Nano-scale Chemical State Visualization of Functional Materials Using Ptychography-XAFS

Nozomu Ishiguro, Yukio Takahshi Tohoku University Ptychography- XAFS, a combination of ptychography imaging using coherent X-rays and XAFS spectroscopy, is one of the most promising tools for visualizing not only the mesoscopic structures but also their

chemical states of the non-uniform materials in nano-scale. Here, we report demonstrations of nano -scale chemical state visualization of practical functional materials using ptychography-XAFS measurements.

[XOPT-5] 14:10-15:10 Application / Detectors

Chair: Satoshi Matsuyama Nagoya University

XOPT-5-01 14:10

Feasibility study on 3D dynamic X-ray elastography for soft tissue and soft materials

Invited

Invited

Invited

Chika Kamezawa¹, Liang Xiaoyu², Tetsuro Shirasawa³, Akio Yoneyama⁴, Kentaro Kajiwara⁵, Kazuyuki Hyodo¹, Wataru Yashiro²

¹Photon Factory, Institute of Materials Structure Science/ KEK, ²Institute of Multidisciplinary Research for Advanced Materials (IMRAM), Tohoku University, ³National Institute of Advanced Industrial Science and Technology (AIST), ⁴SAGA Light Source, ⁵Japan Synchrotron Radiation Research Institute (JASRI) We are developing dynamic x-ray elastography for soft tissue and soft materials. We show preliminary results of three-dimensional maps of storage and loss moduli using white synchrotron x-rays and high speed x-ray camera.

X0PT-5-02 14:30 // Additive Manufacturing for X-ray

optical applications Adam Kubec¹, Frank Seiboth², Mikhail Lyubomirskiy², Frieder Koch¹, Andreas Schropp², Christian David¹, Christian Schroer^{2,3}

¹Paul Scherrer Institut, ²DESY, ³Universität Hamburg

3D-printing allows making various kinds of X-ray optical components. Structures can be made to focus beams, correct for phase existing optics or adding custom phase modifications such as a topological charge, or act as samples.

XOPT-5-03 14:50

CITIUS: a 17400 frames/s X-ray imaging detector with a linear response over 600 Mcps/pixel Takaki Hatsui

RIKEN SPring-8 Center

Recent advances in photon sources deliver intense x-rays on to X-ray imaging detectors; photon counting detectors are challenged due to its limited count rate. The CITIUS detector has been developed to overcome this limitation. Experimental results will be reported with an emphasis on its high dynamic range capability, where CITIUS can detect over 600 Mcps/pixel.

Invited [XOPT-6] 15:20-16:30 FEL-related topics

Chair: Ichiro Inoue RIKEN SPring-8 Center

XOPT-6-01 15:20

Measurement of transient optical phase change as a potential diagnostics tool for extreme-ultraviolet free-electron-laser pump opticalprobe experiments

Invited

Invited

Invited

Victor Tkachenko^{1,2}, Sven Toleikis³, Vladimir Lipp², Beata Ziaja⁴, Ulrich Teubner¹ 'University of Applied Sciences, Emden, Germany, ²Center for Free-Electron Laser Science CFEL, DESY, Hamburg, Germany, ³Deutsches Elektronen-Synchrotron DESY, Hamburg, Germany, 'Institute of Nuclear Physics, Polish Academy of Sciences, Krakow, Poland

Transient optical properties are typical observables in extreme-ultraviolet-pump optical-probe experiments. Here we propose to additionally measure transient phase change of the optical probe pulse. Our computational study demonstrates that, at correctly tuned pulse parameters, such measurement can provide a strong enough signal enabling access to more information on transient state of the taroet.

XOPT-6-02 15:40

A diamond channel cut monochromator for operation at high energy and high repetition rate at the EuXFEL: a numerical modeling of the thermal load effects

Kelin Tasca¹, Ilia Petrov¹, Fang Yang¹, Sergey Terentyev², Maurizio Vannoni¹, Liubov Samoylova¹

¹European X-ray Free Electron Laser, ²Technol Inst Superhard & Novel Carbon Mat

A diamond channel cut monochromator for operation at high energy and high repetition rate at the EuXFEL: a numerical modeling of the thermal load effects will be presented.

XOPT-6-03 16:00

Hanbury Brown and Twiss Interferometry at X-ray Free-Electron Lasers

Ivan Vartaniants Deutsches Elektronen-Synchrotron DESY The basic idea of the Hanbury Brown and Twiss (HBT) interferometry is to determine the statistical properties of radiation from the normalized second-order intensity correlation function obtained by measuring the coincident response at two detector positions. We implemented HBT interferometry at different X-ray freeelectron laser (XFEL) sources from XUV to hard X-ray range. Recent results obtained at European XFEL and PAL XFEL facilities will

[XOPT-7] 16:40-17:40 Novel optics/methods

be presented.

Chair: Makina Yabashi RIKEN SPring-8 Center

X0PT-7-01 16:40 Invited

Thermoelastic stability of Bragg reflectors under pulsed heat load in an XFEL0

Immo Bahns¹, Wolfgang Hillert², Patrick Rauer¹, Joerg Rossbach², Harald Sinn¹ ¹European XFEL, ²Universität Hamburg Thermoelastic stability of Bragg reflectors under pulstic stability of Bragg reflectors under pulstic heat load in an XFELO will be presented.

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X0PT-7-02 17:00

Laboratory based hard X-ray microscopy with Multilayer-Laue-Lens for full-field imaging

Juergen Gluch¹, Peter Gawlitza², Sven Niese³, Reiner Dietsch³, Norman Huber⁴, Ehrenfried Zschech¹

¹ Frauhofer IKTS, ²Fraunhofer IWS, ³AXO DRESDEN GmbH, ⁴Huber Diffraktionstechnik GmbH & Co. KG

A laboratory nano X-ray computed tomography (nano-XCT) system that is designed for the photon energy range > 10 keV and that uses multilayer optics for sample illumination and as objective lens will be presented. A multilayer Laue lens (MLL) is used for full-field imaging. We will demonstrate images of test structures acquired with MLLs at photon energies of 8 keV (Cu-Ka) and 17.5 keV (Mo-Ka).

XOPT-7-03 17:20 Invited Multi-Focus Off-Axis Zone Plates for Experiments at X-Ray Free Electron Lasers Lasers Lasers

Florian Doering^{1,2}, Benedikt Roesner¹, Martin Beye³, Robin Engel³, Loic Le Guyader⁴, Andreas Scherz⁴, Manuel Langer¹, Adam Kubec¹, Armin Kleibert¹, Joerg Raabe¹, Carlos Vaz¹, Christian David¹ ¹Paul Scherrer Institut, ²XRnanotech, ³FLASH/ DESY, ⁴European XFEL We have designed a new type of X-ray optic that combines the beam-splitting functionality of a transmission grating with

functionality of a transmission grating with the focusing capabilities of a zone plate and hence, enables multi-focus experiments at XFELs.

[XOPT-Closing] 17:40-17:50 Closing Remarks Chair: Kazuto Yamauchi *Osaka University*